



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 217623US2S DIV		SERIAL NO. 10/058,099	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE January 29, 2002		GROUP 2615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/SH/	AA	5,778,142	7Jul98	TAIRA, et al.			
/SH/	AB	5,915,067	22Jun99	NONOMURA, et al.			
/SH/	AC	5,999,696	7Dec99	TSUGA, et al.			
/SH/	AD	5,999,698	7Dec99	NAKAI, et al.			
/SH/	AE	6,088,507	11Jul00	YAMAUCHI, et al.			
/SH/	AF	6,094,414	25Jul00	TAIRA, et al.			
/SH/	AG	6,112,011	29Aug00	HISATOMI			
/SH/	AH	6,198,874 B1	6Mar01	KANESHIGE, et al.			
/SH/	AI	6,222,806	24Apr01	MORI, et al.			
	AJ						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/SH/	AO	JP 8-263969	11Oct96	JAPAN	x		
/SH/	AP	JP 60-236163	22Nov85	JAPAN (English Abstract of Japanese Patent)			x
/SH/	AQ	JP 58-088978	27May83	JAPAN (English Abstract of Japanese Patent)			x
/SH/	AR	JP 02-206820	16Aug90	JAPAN (English Abstract of Japanese Patent)			x
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1998-133832 (with English translation)					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Syed Hasan/				Date Considered 10/29/2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>Hideo ANDO, et al.</b>			
				FILING DATE <b>January 29, 2002</b>		GROUP <b>2621</b>	
<b>U.S. PATENT DOCUMENTS</b>							
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES      NO		
/SH/	AO	3898751	03/28/07	JAPAN			
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/SH/	AO	6-223504	08/12/94	Japan			X
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
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10/058,099

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT  
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## U.S. PATENT DOCUMENTS

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/SH/	AO	11-238318	08/31/1999	JAPAN		X
/SH/	AP	8-315551	11/29/1996	JAPAN		X
/SH/	AQ	9-135412	05/20/1997	JAPAN		X
/SH/	AR	10-112166	04/28/1998	JAPAN		X
/SH/	AS	11-162119	06/18/1999	JAPAN		X
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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Examiner

/Syed Hasan/

Date Considered

10/29/2007

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Attorney Docket No. 2 23US-2S DIV

## Notice of References Cited

Application/Control No. New Divisional App.		Applicant(s)/Patent Under Reexamination ANDO ET AL	
Examiner To Be Assigned		Art Unit Unassigned	Page 1 of 1

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*		Document Number		Date	Name	Classification	
		Country	Code-Number-Kind Code				
SH	A	US-	6,212,330-B1	04-2001	Yamamoto et al	386	95
SH	B	US-	6,181,870-B1	01-2001	Okada et al	386	95
	C	US-	-				
	D	US-	-				
	E	US-	-				
	F	US-	-				
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	H	US-	-				
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	J	US-	-				
	K	US-	-				
	L	US-	-				
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### FOREIGN PATENT DOCUMENTS

*		Document Number		Date	Country	Name	Classification	
		Country	Code-Number-Kind Code					
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### NON-PATENT DOCUMENTS

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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.08(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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				FILING DATE HEREWITH		GROUP To be assigned	
<b>U.S. PATENT DOCUMENTS</b>							
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/SH/	AO	58-88978	5/27/83	Japan			X
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